

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KLETTKE ET AL.	
		Examiner Tae H. Yoon	Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,894,144	05-2005	Zech et al.	528/394
B	US-			
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E	US-			
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I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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NON-PATENT DOCUMENTS

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